Supporting Information for

Low energy consumption fiber-type memresistor array with integrated sensingmemory

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Supplementary Text

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Figure S11. The typical *I–V* curve of device with of memorisistor Pt/PEDOT:PSS-ion gel/Au (green line) and Pt/PEDOT:PSS-ion gel/Au(blank line)

Figure S12. The typical *I*–*V* curve of device with P3HT as active material of memorisistor under varied sweep range ($-1 \sim 1V$, $-0.8V \sim 0.8V$, $-0.6V \sim 0.6V$, $-0.4V \sim 0.4V$).

Supplementary Figures

Figure S1



Figure S1. Scanning electron microscopy (SEM) images of Ag-coated (left panel) carbon fibers and Pt-coated (right panel) carbon fibers





Figure S2. The typical I-V curve of device back-forward sweep





Figure S3. The typical *I*–*V* curve of sole PEDOT: PSS(red line) and sole ion gel(blue line).



Figure S4. The typical *I–V* curve of device under varied ion gel recipe(composed of 1-ethyl-3-methylimidazolium bis(trifluoromethyl sulfonyl)imide ([EMIM][TFSI]) ion liquid, poly(ethylene glycol) diacrylate (PEGDA) monomers and 2-hydroxy-2methylpropiophenone (HOMPP) photo-initiator in a weight ratio of 1.72:0.4:0.12 (pink curve) and 4.5:0.4:0.12(blue curve)





Figure S5. The pulse voltage posed on the device and the corresponding *I-t* curve



Figure S6. The typical I-V curve of device under varied compliment currents



Figure S7. The typical I-V curve of device under varied sweep range (-1~1V, - 0.8V~0.8V, -0.6V~0.6V, -0.4V~0.4V)



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Figure S10



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Figure S11. The typical *I–V* curve of device with of memorisistor Pt/PEDOT:PSS-ion gel/Au (green line) and Pt/PEDOT:PSS-ion gel/Au(blank line)



Figure S12. The typical I-V curve of device with P3HT as active material of memorisistor under varied sweep range (-1 \sim 1V, -0.8V \sim 0.8V, -0.6V \sim 0.6V, - 0.4V \sim 0.4V).